

IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST
CERTIFICATES FOR ELECTRICAL EQUIPMENT
(IECEE) CB SCHEME

SYSTEME CEI D'ACCEPTATION MUTUELLE DE
CERTIFICATS D'ESSAIS DES EQUIPEMENTS
ELECTRIQUES (IECEE) METHODE OC

CB TEST CERTIFICATE

Product

IC including capacitor discharge function (ICX)

Name and address of the applicant

ON SEMICONDUCTOR
10F 16 LANE 35 JIHU RD, NEIHU DISTRICT TAIPEI, TAIWAN

Name and address of the manufacturer

ON SEMICONDUCTOR
10F 16 LANE 35 JIHU RD, NEIHU DISTRICT TAIPEI, TAIWAN

Name and address of the factory

ON Semiconductor
5005 East McDowell Rd, Phoenix, AZ, 85008
U.S.A

Note: When more than one factory, please report on page 2

Ratings and principal characteristics

Additional Information on page 2
(Optional) Vcc 30 Vdc max.

Trademark (if any)

ON

Type of Customer's Testing Facility (CTF) Stage used

Model / Type Ref.

DAP029, DAP030, NCP1249x65, NCP1339x, NCP1339xG,
SCY99127, SCY99142 See Page 2

Additional information (if necessary may also be
reported on page 2)

Additional Information on page 2

A sample of the product was tested and found
to be in conformity with

IEC 62368-1(ed.2)

As shown in the Test Report Ref. No. which forms
part of this Certificate

E486692-4787566709-3 Original issued on 2017-03-21

This CB Test Certificate is issued by the National Certification Body



UL (US), 333 Pfingsten Rd IL 60062, Northbrook, USA

UL (Demko), Borupvang 5A DK-2750 Ballerup, DENMARK

UL (JP), Marunouchi Trust Tower Main Building 6F, 1-8-3 Marunouchi, Chiyoda-ku, Tokyo 100-0005, JAPAN

UL (CA), 7 Underwriters Road, Toronto, M1R 3B4 Ontario, CANADA

For full legal entity names see www.ul.com/ncbnames

Date: 2017-03-23

Signature:

Jan-Erik Storgaard



Ref. Certif. No.

DK-62211-UL

Model Details:

NCP1249x65 (x = A, B, C or D)
NCP1339x,NCP1339xG (x = C, D, E, F, G, H, I or J)

Factories:

ON Semiconductor Philippines INC
Golden Mile Business Park Special Economic Zone Governors Dr, Carmona, Cavite
Philippines

Additional Information:

Additionally evaluated to EN 62368-1:2014/A11:2017; National differences specified in the CB Test Report.

Additional information (if necessary)

Information complémentaire (si nécessaire)



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- UL (Demko), Borupvang 5A DK-2750 Ballerup, DENMARK
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